

LOW POWER FULL ADDER USING GROUND BOUNCE NOISE TECHNOLOGY

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ABSTRACT

Static leakage power consumption and ground bounce noise at nanometer scale are two important parameters, to keep in consideration are compactness and power which affects the performance of any VLSI circuits. Full adder is the vital part of digital circuits which employ arithmetic operation. Adder circuit is widely used in many digital circuits for arithmetic operation as well as an adder for address generation in many processors and microcontrollers. So we need to choose which one should be employed in large scale system at higher speed. It is necessary to make these systems more efficient so as to survive with high speed while consuming low power. As the speed of the circuit increases, the most unwanted parameter that is exhibited by the circuits is ground bounce noise. This paper here describes how the reduction of leakage power and ground bounce noise from the 14T full adder circuits can be made to make it more reliable to be used with high speed system. All the simulation in this paper has been carried out using tanner eda tool.

Keywords:- ground bounce noise, power consumption, variable body bias.

1.INTRODUCTION

The adders play an important role in complex arithmetic's and computational circuits such as multiplier, compressor, comparator and parity checkers. In recent years, many approaches have been proposed to implement a low power full adder. The aim of this paper is to implement a full adder to reduce power and analyze the noise using ground bounce noise technology. For application of electronic devices, designers have to work with objects within very less leakage power and they need to meet the specification of product battery life as well as package cost[1]. This paper aims at design, analysis and improvement of power efficiency and ground bounce noise reduction of the 14T full adder using Tanner EDA technology. In this paper, we have proposed to design techniques with 14T adder to reduce static power dissipation as well as ground bounce noise. The power reduction in any logic circuit cannot be simply achieved by trading off performance because it makes it even harder to reduce the leakage during run time operation. We have already seen several techniques for reducing the leakage power.

This paper describes proposed stacking power technique where we insert a sleep transistor between active ground rail and virtual ground. The main idea behind this technique is that the device is turned off in sleep mode and also the cut off leakage path provides a reduced leakage power with improved performance in power and reduced ground bounce noise using novel technique with improved stacking and power gating. Low power has emerged as a principal theme in today's world of electronics industries [5]. Power dissipation has become an important consideration as performance and area for VLSI Chip design [4]. With shrinking technology reducing power consumption and over all power management on chip are the key challenges below 100nm due to increased complexity. For many designs, optimization of power is important as timing due to the need to reduce package cost and extended battery life. For power management leakage current also plays an important role in low power VLSI designs[2]. Leakage current is becoming an increasingly important fraction of the total power dissipation of integrated circuits [3]. An adder is one of the most critical components of a processor which determines its throughput, as it is used in the ALU, the floating-point unit, and for address generation in case of cache or memory access [6]. Recently there have been several attempts to design energy recovering logic in the pursuit of energy efficient circuitry. In this paper we are going to design a ultra low power 14 Transistor adder using the novel stacking power gating logic which has very low leakage power.

2.14T FULL ADDER:

Full adder has been derived with various structures previously to reduce the power dissipation as well as area reduction. To analyze the different parameters of adders, we use the 14T full adder as our base structure. The structure shown in Fig.(1) uses the pass transistor logic for leakage and also for area reduction. However still having less number of transistors as well as reduced leakage, the 14T adder suffers from the ground bounce noise problem. The ground bounce noise does not affect the circuits which operate at lower clock frequencies. At higher frequencies, the switching due to the ground bounce noise will change the state of the actual output. The reduce ground bounce noise 14T adder are shown in Fig. (2) and Fig. (3). To decrease the ground bounce noise and leakage power, we need to propose a modified design with the stacking power gating technique. Here it is connected to the virtual ground of the circuits so as to reduce the magnitude of voltage glitches and current and also the reduction of leakage power by stacking effect, when both the sleep transistor with ST1 and ST2 are turned off. Here with help of the selected inputs we have reduced ground bounce noise and this is achieved by the adjusting both the transistors with the help of ΔT (delay between the both sleep transistor) (sleep to active mode).

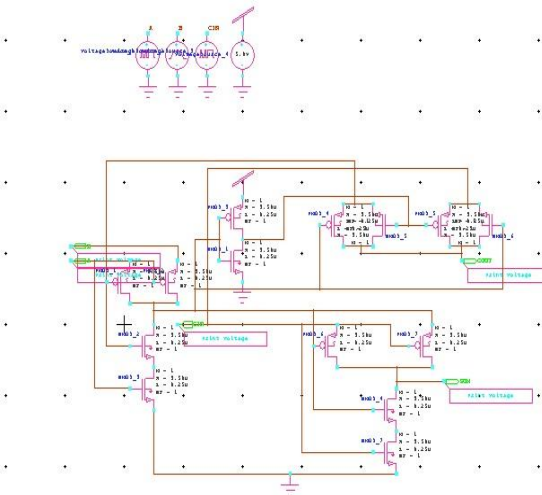


Fig:1 14T full adder

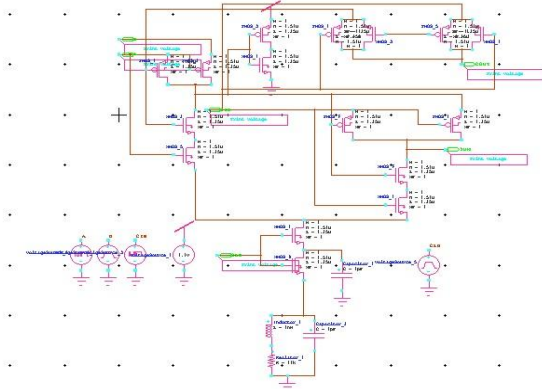


Fig:2 14T full adder with stacking power gating

2.1: GROUND BOUNCE NOISE

The high edge speeds and clock frequencies of advanced CMOS technology can produce unwanted oscillations during logic level transitions resulting in random logic bit errors[6]. Designers can spend countless hours searching for the causes of these errors and might completely overlook the effects that pico farad capacitance and nano henry inductance in ground loop circuits can have on the digital IC power supply ground potential. Voltage drops across these small, reactive component elements can result in ground level shifts or "bounce." The bounce, when added to the device logic level, may be sufficient to erroneously toggle a flip-flop in a neighboring or succeeding logic stage. Fortunately, with an understanding of what influences ground bounce, you can measure it and take corrective action. Figure 1 is a simplified model of a digital circuit. LP is the inductance of the IC package, which includes the lead frame and bond wires[7-8]. This can be as large as 20 nH for dual inline package styles. Lc is the inductance of the PCB trace between C1 and the power supply bypass capacitor (typically 0.1 μ F)[8]. Depending on board layout, Lc can be up to 100 nH. CL is the distributed load

capacitance between the PCB trace on the output pin and ground. The load capacitance, which varies with board design, is typically 50 pF. During logic level transitions, the rapid charging and discharging of CL results in an inductive $L(di/dt)$ voltage drop across LPVCC and LPGND. Voltage drop across LPGND causes the IC ground potential to rise above the power supply ground potential. Other ICs may see this effect as a logic change on the output of the device. When the IC input returns high, ground bounce of the opposite polarity occurs due to the voltage drop across LPVCC.

2.2 VARIABLE BODY BIAS:

In statistics, omitted-variable bias (OVB) occurs when a model is created which incorrectly leaves out one or more important causal factors. The "bias" is created when the model compensates for the missing factor by over- or underestimating the effect of one of the other factors. More specifically, OVB is the bias that appears in the estimates of parameters in a regression analysis, when the assumed specification is incorrect in that it omits an independent variable that is correlated with both the dependent variable and one or more included independent variables.

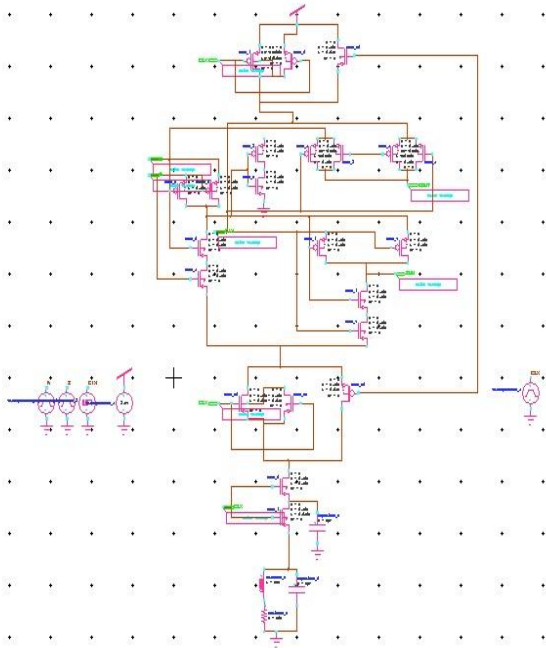


Fig:3 14T full adder using variable body bias technique

3. SIMULATION RESULTS:

This is the result for a normal 14T full adder to find the power consumption.

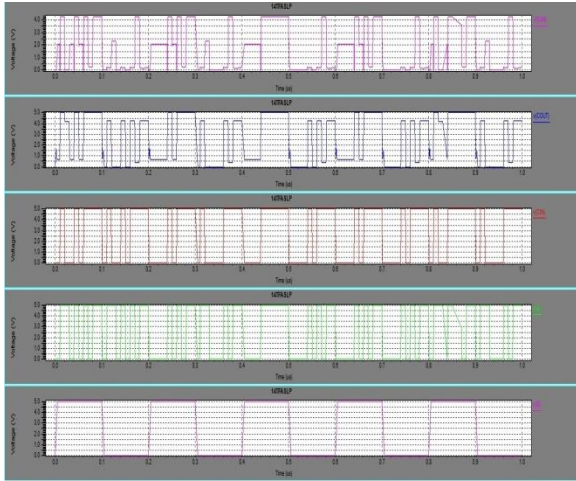


Fig 4: simulation result for a normal 14T full adder

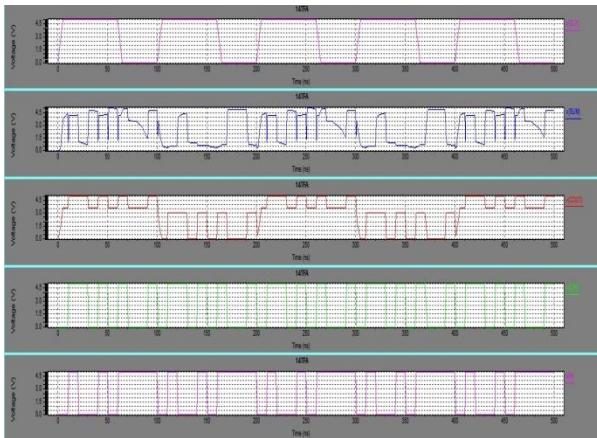


Fig 5: simulation result for 14T full adder with stacking power gating

Table:1 power comparison of 14T full adder with and without stacking power gating

Parameter	14T full adder	14T full adder with stacking power gating	14T full adder with variable body bias

Average power	3.199e-11 (watts)	2.154e-11 (watts)	1.142e-11 (watts)
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The average power for a 14T full adder with and without stacking power gating and variable body bias is observed in the above table.

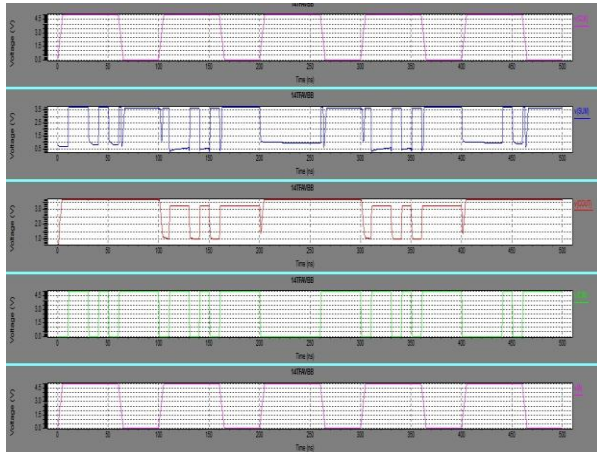


Fig 6: simulation result for 14T full adder using variable body bias technique.

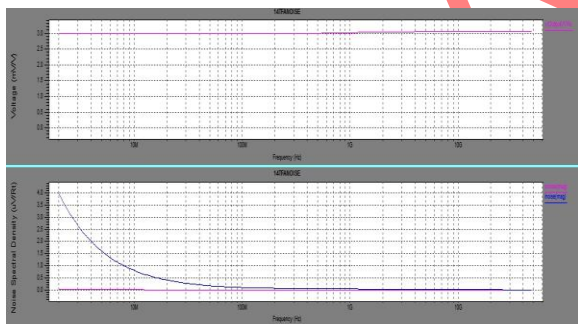


Fig:7 Noise analysis.

Table 2: Comparison between input noise and output noise for 14t full adder

Frequency (Hz)	Input noise(magnitude)	Output noise(magnitude)
2.0e6	3.98e-6	1.19e-8
3.02e6	2.63e-6	7.87e-9

4.17e6	1.91e-6	5.70e-9
5.02e6	1.58e-6	4.74e-9
6.03e6	1.32e-6	3.94e-9
7.26e6	1.10e-6	3.23e-9

The above table depicts the difference in the input noise and output noise obtained for 14T full adder. Here we vary the frequencies and find the magnitude of the input and output respectively.

4 CONCLUSION:

In this paper we proposed a modified 14T full adder for microprocessor and arithmetic logic circuit with low ground bounce noise and reduced leakage power. Here we have used high performance power gating technique to reduced active power and ground bounce noise. We had reduced the power consumption by 66.66 percent using variable body bias method and 33.33 percent decrease in power using stacking power gating method. Noise analysis is carried out for 14T full adder.

5. REFERENCES:

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